

Search Notes



Application/Control No.

09/840,892

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

SATO ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	7/1/05	oon
	7		
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	9		
	14 ^o		
	16 ^x		
	26 ^x		
	27 ^x		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	7/1/05	oon
1. PG Pub 2. Patent	↓	↓
II FOREIGN	7/1/05	↓
1. EPO 2. JPO 3. Derwent	↓	↓
III 4. IBM-TDB 5. O S O CSR	↓	↓